

Situated within Horowhenua County at Ohau:

Muhunua West Road: from No. 1 State Highway (Awanui-Bluff) to a point 50 metres measured westerly, generally, along the said road from Jervois Terrace.

Muhunua East Road: from No. 1 State Highway (Awanui-Bluff) to a point 50 metres measured easterly, generally, along the said road from Railway Terrace.

Jervois Terrace.
Marsden Terrace.
Victoria Terrace.

SECOND SCHEDULE

SITUATED within Horowhenua County adjacent to Levin Borough:
Fairfield Road: from the northern boundary of Levin Borough to Roslyn Road.

Roslyn Road.

Signed at Wellington this 31st day of October 1986.

C. M. CLISSOLD, Chief Traffic Engineer.

†*New Zealand Gazette*, No. 89, dated 12 June 1986, page 2491
(M.O.T. 29/2/Horowhenua County)

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The Standards Act 1965—Overseas Specifications Endorsed as Suitable for use in New Zealand

PURSUANT to section 17 of the Standards Act 1965, the Standards Council, on 26 September 1986, endorsed the under-mentioned overseas specifications as suitable for use in New Zealand.

Number and Title of Specification	Price of Copy (Post free) Plus G.S.T. \$
<i>International Electrotechnical Commission</i>	
IEC 68:— Basic environmental testing procedures— 68-2-52(1984) Test Kb: Salt mist, cyclic (sodium chloride solution).	36.00
68-2-53(1984) Guidance to tests Z/AFc and Z/BFc: Combined temperature (cold and dry heat) and vibration (sinusoidal) tests.	30.00
IEC 107:— Recommended methods of measurement on receivers for television broadcast transmissions— 107-1(1977) Part 1: General considerations. Electrical measurements other than those at audio-frequencies.	363.00
IEC 115:— Fixed resistors for use in electronic equipment— 115-7(1984) Part 7: Sectional specification: Fixed resistor networks in which not all resistors are individually measurable.	96.00
115-7(1984) Part 7: Blank detail specification: Fixed resistor networks in which not all resistors are individually measurable. Assessment level E.	58.50
IEC 131:— Level switches— 131-1(1984) Part 1: General requirements and rules for the preparation of detail specifications.	63.00
131-2(1963) Part 2: Requirements for switches of Type 1, slow-make, slow-break.	27.00
131-3(1969) Part 3: Requirements for switches of Type 2, quick-make, quick-break (toggle switches).	18.00
IEC 147:— Essential ratings and characteristics of semiconductor devices and general principals of measuring methods 147-0F(1982) Sixth supplement.	102.00
IEC 150(1963) Testing and calibration and ultrasonic therapeutic equipment	27.00
IEC 163:— Sensitive switches— 163-1(1984) General requirements and rules for the preparation of detail specifications.	73.50
IEC 191:— Mechanical standardisation of semiconductor devices— 191-2L(1982) Eleventh supplement.	54.00
191-2M(1983) Twelfth supplement.	48.00
IEC 248(1984) Dimensions of plachets used in nuclear electronic instruments.	25.50
IEC 297:— Dimensions of mechanical structures of the 482.6 mm (19 in.) series— 297-3(1984) Part 3: Subracks and associated plug-in units.	63.00
IEC 326:— Printed boards— 326-1(1984) Part 1: General information for the specification writer.	46.50
IEC 384:— Fixed capacitors for use in electronic equipment— 384-1(1982) Part 1: Generic specification.	129.00
384-2(1982) Part 2: Sectional specification: Fixed metallized polyethylene terephthalate film dielectric d.c. capacitors.	112.50
384-2-1(1982) Part 2: Blank detail specification: Fixed metallized polyethylene terephthalate film dielectric d.c. capacitors. Assessment level E.	52.50
384-13(1980) Part 13: Sectional specification: Fixed polypropylene film dielectric metal foil capacitors for direct current. Selection of methods of test and general requirements.	70.50
384-14(1981) Part 14: Sectional specification: Fixed capacitors for radio interference suppression. Selection of methods of test and general requirements.	114.00
384-15-1(1984) Part 15: Blank detail specification: Fixed tantalum capacitors with non-solid electrolyte and foil electrode. Assessment level E.	57.00
384-15-2(1984) Part 15: Blank detail specification: Fixed tantalum capacitors with non-solid electrolyte and porous anode. Assessment level E.	57.00
384-15-3(1984) Part 15: Blank detail specification: Fixed tantalum capacitors with solid electrolyte and porous anode. Assessment level E.	57.00
IEC 457:— Rigid precision coaxial lines and their associated precision connectors— 457-5(1984) Part 5: 50 ohms 3.5 mm rigid precision coaxial line with provision for mounting connectors.	16.50
IEC 487:— Methods of measurement for equipment used in terrestrial radio-relay systems— 487-1(1984) Part 1: Measurements common to sub-systems and simulated radio-relay systems.	190.50
487-2-3(1984) Part 2: Measurements for sub-systems. Section 3—R.F. branching networks.	34.50
IEC 489:— Methods of measurement for radio equipment used in the mobile services— 489-8(1984) Part 8: Methods of measurement for antennas.	57.00
IEC 512:— Electromechanical components for electronic equipment; basic testing procedures and measuring methods— 512-1(1984) Part 1: General.	49.50
512-2A(1980) First supplement to 512-2 publication.	
512-3(1976) Part 3: Current-carrying capacity tests.	
512-4(1976) Part 4: Dynamic stress tests.	
512-5(1977) Part 5: Impact tests (free components), static load tests (fixed components), endurance tests and overload tests.	64.50
512-5A(1980) First supplement.	24.00
512-5B(1981) Second supplement.	25.50
512-6(1984) Part 6: Climatic tests and soldering tests.	114.00
512-7(1978) Part 7: Mechanical operating tests and sealing tests.	49.50
512-8(1984) Part 8: Connector tests (mechanical) and mechanical tests on contacts and terminations.	115.50
IEC 574:— Audio-visual, video and television equipment and systems— 574-15(1984) Part 15: Audio pages.	25.50
IEC 620(1984) Dimensions for the mounting of single-hole, bush-mounted, spindle-operated, electronic components.	57.00
IEC 745:— Safety of hand-held motor-operated electric tools— 747-5(1984) Part 5: Optoelectronic devices.	124.50
747-8(1984) Discrete devices. Part 8: Field-effect transistors.	153.00
747-10(1984) Part 10: Generic specification for discrete devices and integrated circuits.	111.00